

# Metal Oxide Semiconductor Capacitor

# Problem - 1

An Al-gate n-channel MOS device is made on a p-type Si substrate with  $N_A = 10^{17} \text{ /cm}^3$ . The  $\text{SiO}_2$  thickness is  $100 \text{ \AA}$  in the gate region, and the effective interface charge  $Q_i$  is  $5 \times 10^{10} q \text{ C/cm}^2$ .

- (a) Find maximum depletion width, flat band voltage and threshold voltage.
- (b) Sketch the C-V curve for this device and give important numbers for the scale.

# Problem - 2

An Al-gate p-channel MOS device is made on an n-type Si substrate with  $N_D = 10^{17} \text{ /cm}^3$ . The  $\text{SiO}_2$  thickness is  $100 \text{ \AA}$  in the gate region, and the effective interface charge  $Q_i$  is  $5 \times 10^{10} q \text{ C/cm}^2$ .

- (a) Find maximum depletion width, flat band voltage and threshold voltage.
- (b) Sketch the C-V curve for this device and give important numbers for the scale.

# Problem - 3

Find the threshold voltage for a Si n-channel MOS transistor with  $N_A = 10^{17} \text{ /cm}^3$ ,  $\Phi_{ms} = -0.95 \text{ V}$ ,  $Q_i = 10^{11} q \text{ C/cm}^2$ , and an  $\text{SiO}_2$  thickness  $d = 200 \text{ \AA}$ .

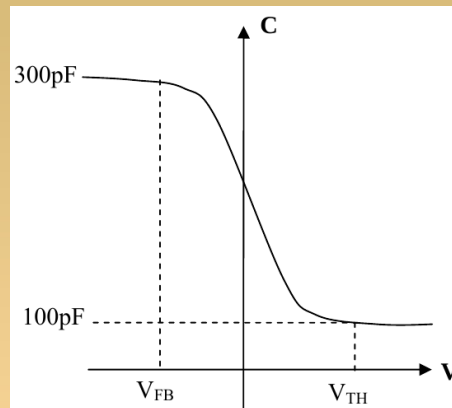
# Problem - 4

(a) Find the voltage  $V_{FB}$  required to reduce to zero the negative charge induced at the semiconductor surface by a sheet of positive charge  $Q_{ox}$  located  $x'$  below the metal.

(b) In case of an arbitrary distribution of charge  $\rho(x')$  in the oxide, show that

$$V_{FB} = \frac{-1}{C_{ox}} \int_0^d \rho(x') dx'$$

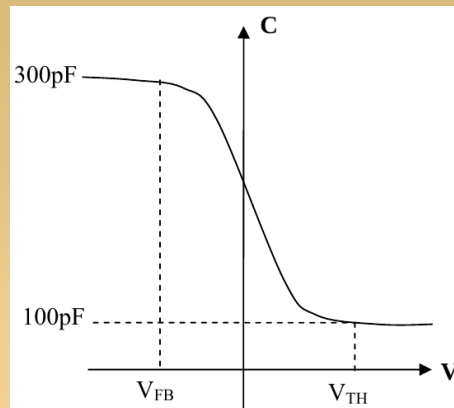
# Problem - 5



From the given C-V characteristics of a MOS capacitor, pick the correct statement below:

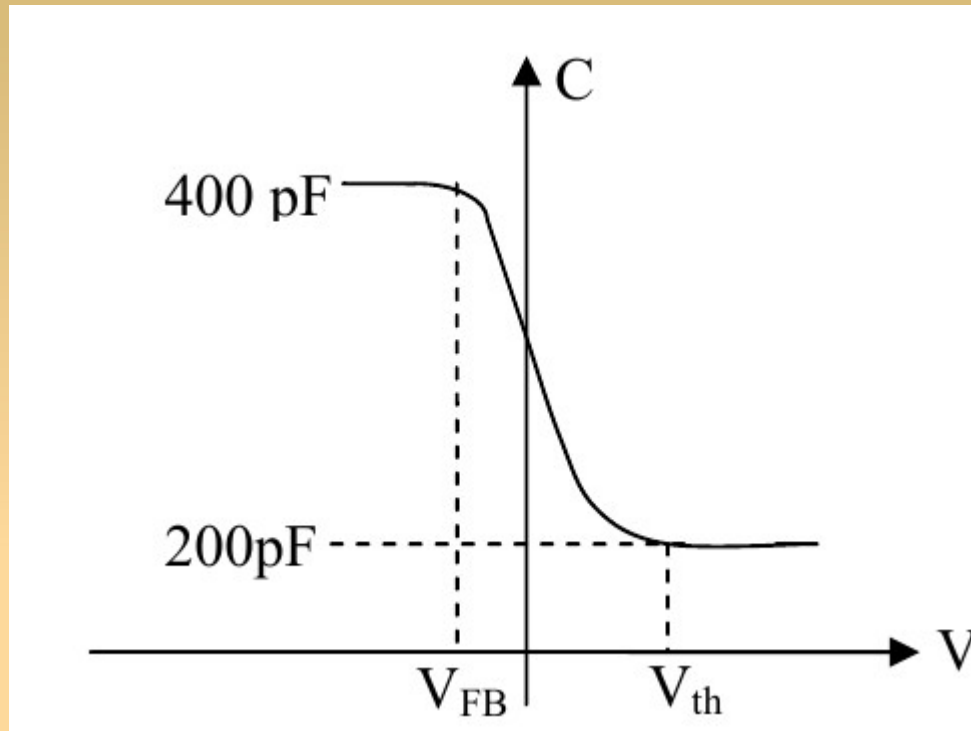
- (A) The substrate is n-type and the measurement is done at low frequency.
- (B) The substrate is p-type and the measurement is done at low frequency.
- (C) The substrate is n-type and the measurement is done at high frequency.
- (D) The substrate is p-type and the measurement is done at high frequency.

# Problem - 6



For the given C-V characteristics of a MOS capacitor with an area of  $1.5 \text{ mm}^2$ . What is the maximum depletion layer width ( $W_{\text{max}}$ ) in  $\mu\text{m}$ ?

# Problem - 7



In the given figure, if the area of the capacitor is  $1 \text{ mm}^2$ ,

(a) what is the gate oxide thickness ( $t_{ox}$ )?

(b) what is the maximum depletion layer width ( $W_{max}$ )?



# Problem - 8

If the area of a MOS capacitor is  $1 \text{ mm}^2$  and the gate oxide thickness ( $t_{\text{ox}}$ ) is  $100 \text{ nm}$ ,

(a) what is  $C_{\text{max}}$ ?

(b) if  $C_{\text{min}} = 0.5C_{\text{max}}$ , what is the maximum depletion layer width ( $W_{\text{max}}$ )?

## Problem - 9

A MOS capacitor has an area of  $2 \times 10^{-3} \text{ cm}^2$ . The substrate doping concentration is  $10^{16}/\text{cm}^3$ . If the maximum and minimum capacitances of the MOS capacitor are 350 pF and 200pF respectively, what is the maximum depletion width?

# Problem - 10

In a metal/SiO<sub>2</sub>/p-Si MOS capacitor, the SiO<sub>2</sub> layer thickness is  $t_{ox}$  and the doping concentration of the p-type substrate is  $N_A$ . The threshold voltage of the MOS capacitor will definitely increase if

- (A)  $t_{ox}$  is decreased and  $N_A$  is increased
- (B)  $t_{ox}$  is increased and  $N_A$  is decreased
- (C) both  $t_{ox}$  and  $N_A$  are decreased
- (D) both  $t_{ox}$  and  $N_A$  are increased.